

Notice of References Cited		Application/Control No. 09/639,441	Applicant(s)/Patent Under Reexamination OKUNIEWICZ, DOUGLAS M.	
		Examiner Binh-An D. Nguyen	Art Unit 3713	Page 1 of 3

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Notice of References Cited		Application/Control No. 09/639,441	Applicant(s)/Patent Under Reexamination OKUNIEWICZ, DOUGLAS M.	
		Examiner Binh-An D. Nguyen	Art Unit 3713	Page 2 of 3

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Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/639441	OKUNIEWICZ, DOUGLAS M.	
	Examiner	Art Unit	Page 3 of 3
Binh-An D. Nguyen	3713		

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